

Notice of References Cited	Application/Control No.	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner Edward Wojciechowicz	Art Unit 2815	Page 1 of 1

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	C	US-6,727,131	04-2004	Wu et al.	438/199
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	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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